

**靜電放電測試報告****Electrostatic Discharge (ESD) Testing Report**

Applicant/Department: 新德/鄭香旻	
Product: CS213	Case NO: 060106012QES
Test Item: Human Body Model (HBM)	Package/Pin Count: SOT 6
Application Date: 1/5/2006	Date Finished: 1/6/2006
Test Method: MIL-STD-883E Method 3015.7 notice 8	Temperature: 25 \pm 5 $^{\circ}$ C Humidity: 55% \pm 10%RH
Test Equipment: Thermo Keytek Zapmaster 7/4 tester	
Failure Criteria: Device no longer meets the parts drawing requirements using parametric, functional .	
Test Voltage: 1000V(+/-)~2000V(+/-) Step: 500V	

HUMAN-BODY MODEL TESTING Result

MODEL: HBM	ESD SENSITIVITY PASS: <u>$\pm 2000V$</u>		V CLASS: 2 NOTE: FOR MIL-STD CLASS1: 0V to 1999V CLASS2: 2000 to 3999V CLASS3: 4000 to above
PIN COMBINATION	SAMPLE SIZE	PASSED VOLTS	
I/O(+)-VDD	3	+2000V	
I/O(-)-VDD	3	-2000V	
I/O(+)-VSS	3	+2000V	
I/O(-)-VSS	3	-2000V	
VDD(+)-VSS	3	+2000V	
VDD(-)-VSS	3	-2000V	

Pin Assignment

I/O:1 2 3

VDD:5

VSS:6

Remark:

This report refers only to the specimen submitted to testing, and be invalid as separately used.

Testing Engineer: Vickof Su	Approved by: [Signature]
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**I/O(+)-VDD**

(Unit: V)

Test Fail Pin Voltage	#01	#02	#03	Test Fail Pin Voltage	#01	#02	#03
1	Pass	Pass	Pass	3	Pass	Pass	Pass
2	Pass	Pass	Pass				

I/O(-)-VDD

(Unit: V)

Test Fail Pin Voltage	#01	#02	#03	Test Fail Pin Voltage	#01	#02	#03
1	Pass	Pass	Pass	3	Pass	Pass	Pass
2	Pass	Pass	Pass				

I/O(+)-VSS

(Unit: V)

Test Fail Pin Voltage	#01	#02	#03	Test Fail Pin Voltage	#01	#02	#03
1	Pass	Pass	Pass	3	Pass	Pass	Pass
2	Pass	Pass	Pass				

I/O(-)-VSS

(Unit: V)

Test Fail Pin Voltage	#01	#02	#03	Test Fail Pin Voltage	#01	#02	#03
1	Pass	Pass	Pass	3	Pass	Pass	Pass
2	Pass	Pass	Pass				

VDD(+)-VSS

(Unit: V)

Test Fail Pin Voltage	#01	#02	#03	Test Fail Pin Voltage	#01	#02	#03
5	Pass	Pass	Pass				

VDD(-)-VSS

(Unit: V)

Test Fail Pin Voltage	#01	#02	#03	Test Fail Pin Voltage	#01	#02	#03
5	Pass	Pass	Pass				



HBM DESCRIPTION:

THE HBM SIMULATES THE ACTION OF HUMAN BODY DISCHARGING ACCUMULATED STATIC CHARGE THROUGH A DEVICE, AND EMPLOYS A SERIES RC NETWORK CONSISTING OF A 100PF CAPACITOR AND A 1500OHM RESISTOR. BOTH POSITIVE AND NEGATIVE STRESS ARE USED FOR THIS TEST.

HBM REFERENCE STANDARDS:

1. MIL-STD_883E METHOD 3015.7 NOTICE 8
2. JEDEC STANDARD_JESD22-A114-C
3. ESDA_STM5.1-1998

ESD TESTING EQUIPMENT:

THERMO KEYTEK ZAPMASTER 256PIN ESD/LATCHUP TESTER



THERMO KEYTEK MK.2 768PIN ESD/LATCHUP TESTER

